

FORM 1449					Atty. Docket No. P29771		Application No. 10/576.023	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)					Applicant Kimiaki TOSHIKIYO			
					I.A. Filing Date December 15, 2004		Group 2622	
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	A	5561558	10/01/1996	Shiono et al.				
	B	5742433	04/21/1998	Shiono et al.				
	C	2003/0179457	09/25/2003	Dobashi et al.				
	D	7250973	07/31/2007	Dobashi et al.				
	E							
	F							
	G							
	H							
	I							
	J							
	K							
	L							
	M							
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	ENGLISH ABSTRACT YES
	N	2003-243638	08/29/2003	JAPAN				X
	O	2004-096358	03/25/2004	JAPAN				X
	P	7-113907	05/02/1995	JAPAN				X
	Q	7-113906	05/02/1995	JAPAN				X
	R							
	S							
	T							
	U							
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	1	Donald C. O'Shea et al., "Diffractive Optics Design, Fabrication, and Test", SPIE PRESS, pp.54-56, 12/29/2003.						
	2	Toshikiyo et al., "A MOS Image Sensor with Microlenses Built by Sub-Wavelength Patterning", 2007 IEEE ISSCC session 28.8 K, 02/14/2007.						
	3	JAPAN Office action, mail date is 03/22/2011.						
	4	Response to an Office Action to the corresponding Chinese patent application No. 200480042730.2 (with a partial English translation of relevant portion).						
	5							
EXAMINER /Dwight Alex C Tejano/					DATE CONSIDERED 05/07/2011			
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